

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/553,684	YATABE, FUMIO	
Examiner		Art Unit		Page 1 of 1
Hai H. Huynh		3747		

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	L	US-			
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**NON-PATENT DOCUMENTS**

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